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TC 3700 Inventor Search Program

See attached inventor searches for applications and/or patents to help resolve questions of overlapping subject matter. These searches are provided as an initial examination aid: examiners should perform updated or expanded PALM or EAST inventors searches as appropriate.

Serial Number:

1.) See <u>attached</u> printout of inventors listed in PALM

2.) See <u>attached</u> EAST Inventor Search Printout shows Inventor search terms

US 20050270490 A1	US- PGPUB	20051208	36	CORRECTION- FACTOR DETERMINATION APPARATUS AND METHOD	351/246	351/205	Mihashi, Toshifumi et al.
US 20050270484 A1	US- PGPUB	20051208	19	Portable ophthalmic apparatus and ophthalmic system	351/206		Maeda, Naoyuki et al.
US 20050219461 A1	US- PGPUB	20051006		Opthalmological apparatus	351/205	351/221	Hirohara, Yoko
US 20050134798 A1	US- PGPUB	20050623		Device for measuring optical charateristic of eye	351/221		Hirohara, Yoko et al.
US 20050099599 A1	US- PGPUB	20050512		Eye characteristic measuring apparatus	351/205		Mihashi, Toshifumi et al.
US 20050073647 A1	US- PGPUB	20050407		Eye optical characteristic measuring instrument	351/200		Mihashi, Toshifumi et al.
US 20050046793 A1	US- PGPUB	20050303		Eye characteristic measuring apparatus	351/200		Hirohara, Yoko et al.
US 20040212781 A1	US- PGPUB	20041028		Ophthalmologic apparatus	351/221		Mihashi, Toshifumi et al.
US 20040179318 A1	US- PGPUB	20040916		Switching device	361/115		Hashimoto, Hiroaki et al.
US 20040130678 A1	US- PGPUB	20040708		Opthalmic measuring apparatus	351/205		Hirohara, Yoko et al.
US 20040095556 A1	US- PGPUB	20040520		Contrast chart apparatus, contrast sensitivity measuring apparatus, and contrast sensitivity measuring method	351/238		Mihashi, Toshifumi et al.
US 20040080713 A1	US- PGPUB	20040429		Ophthalmic measuring apparatus	351/221		Hashimoto, Hiroaki et al.
US 20040070730 A1	US- PGPUB	20040415		Eye characteristic measuring device	351/221		Mihashi, Toshifumi et al.
US 20040012760	US- PGPUB	20040122		Eye characteristics measuring device	351/205		Mihashi, Toshifumi

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A1						et al.
US 20030189690	US- PGPUB	20031009	Optical characteristics measuring device	351/221		Mihashi, Toshifumi
A1 US 20030174280	US- PGPUB	20030918	 Model eye for eye characteristic	351/200		et al. Yamaguchi, Tatsuo et
A1			 measuring device and calibration method for the same			al.
US 20030164923 A1	US- PGPUB		Best corrected visual acuity characteristics measuring device, best corrected visual acuity characteristics measuring method, contrast sensitivity	351/216		Hirohara, Yoko et al.
			 measuring device, contrast sensitivity measuring method, and contrast sensitivity target displaying device			
US 20030115596 A1	US- PGPUB	20030619	Commercial distribution system, commercial processing apparatus, commercial processing method, and commercial processing program	725/34	725/32	Okajima, Takahiro et al.
US 20030090627 A1	US- PGPUB	20030515	Ophthalmic characteristic measuring apparatus	351/211		Hirohara, Yoko et al.
US 20030043789 A1	US- PGPUB	20030306	Channel switching apparatus, channel switching method and channel switching program	370/360	370/375	Okajima, Takahiro et al.
US 20030011757 A1	US- PGPUB	20030116	OPTICAL CHARACTERISTIC MEASURING INSTRUMENT	356/6		Hirohara, Yoko et al.
US 20030007777 A1	US- PGPUB	20030109	 Commercial cut apparatus, commercial cut method, recording-reproducing	386/46	358/908	Okajima, Takahiro et al.

US 20020184633 A1	US- PGPUB	20021205	apparatus comprising commercial cut function, and commercial cut program Preselection apparatus, preselection method, preselection program, recorder, and recording medium	725/50	725/58	Okajima, Takahiro et al.
US 20020163623 A1	US- PGPUB	20021107	Opthalmic characteristic measuring apparatus	351/212		Hirohara, Yoko et al.
US 20020097625 A1	US- PGPUB	20020725	Semiconductor memory device with a self refresh mode	365/222		Hashimoto, Hiroaki
US 20020041359 A1	US- PGPUB	20020411	Eye characteristic measuring apparatus	351/221		Mihashi, Toshifumi et al.
US 20010035939 A1	US- PGPUB	20011101	Eye characteristic measuring apparatus	351/212		Mihashi, Toshifumi et al.
US 7009130 B2	USPAT	20060307	Switching device	200/400	218/154	Hashimoto; Hiroaki et al.
US 6905209 B2	USPAT	20050614	Optical characteristics measuring device	351/221		Mihashi; Toshifumi et al.
US 6860603 B2	USPAT	20050301	BEST CORRECTED VISUAL ACUITY CHARACTERISTICS MEASURING DEVICE, BEST CORRECTED VISUAL ACUITY CHARACTERISTICS MEASURING METHOD, CONTRAST SENSITIVITY MEASURING DEVICE, CONTRAST SENSITIVITY MEASURING	351/216		Hirohara; Yoko et al.

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			METHOD, AND CONTRAST SENSITIVITY TARGET DISPLAYING DEVICE			
US 6802609 B2	USPAT	20041012	Eye characteristic measuring apparatus	351/221		Mihashi; Toshifumi et al.
US 6695450 B2	USPAT	20040224	Ophthalmic characteristics measuring apparatus	351/211	351/221	Hirohara; Yoko et al.
US 6685320 B2	USPAT	20040203	Opthalmic characteristic measuring apparatus	351/221	351/212	Hirohara; Yoko et al.
US 6654302 B2	USPAT	20031125	Semiconductor memory device with a self refresh mode	365/222	365/233	Hashimoto; Hiroaki
US 6629761 B1	USPAT	20031007	Eye characteristic measuring apparatus	351/221		Hirohara; Yoko et al.
US 6536900 B2	USPAT	20030325	Eye characteristic measuring apparatus	351/221	·	Mihashi; Toshifumi et al.
US 6525883 B2	USPAT	20030225	Optical characteristic measuring instrument	359/618	351/212	Hirohara; Yoko et al.
US 6446227 B1	USPAT.	20020903	Semiconductor memory device	714/719	714/721	Hashimoto; Hiroaki
US 6378091 B1	USPAT	20020423	Test mode circuit capable of surely resetting test mode signals	714/724	714/718; 714/733	Hashimoto; Hiroaki
US 6354705 B1	USPAT .	20020312	Anterior segment photographing apparatus for producing images of a section of the anterior	351/214		Hirohara; Yoko et al.
			segment of the eye to be examined by using slit light beam			
US 6160745 A	USPAT	20001212	Semiconductor storage device	365/200	365/201	Hashimoto; Hiroaki
US 5936910 A	USPAT	19990810	Semiconductor memory device having burn-in test function	365/230.06	365/201; 365/226	Hashimoto; Hiroaki
US 5709106	USPAT	19980120	Condenser structure	62/507	62/509	Inaba;

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A			with liquid tank		Hiroyuki et
					al.
US D361646	USPAT	19950822	Aquarium tank	D30/101	Hashimoto;
S					Hiroaki
US D361170	USPAT	19950808	Aquarium tank	D30/101	Hashimoto;
S					Hiroaki
US D357556	USPAT	19950418	Aquarium tank	D30/101	Hashimoto;
S					Hiroaki
US D356404	USPAT	19950314	Aquarium tank	D30/101	Hashimoto;
S					Hiroaki

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